

**ACTIVITY II: ALICE ITS READOUT
ELECTRONICS
SERIAL LINK CHARACTERIZATION**

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TASKS

- Firmware development for serial link characterization
 - GUI
 - BET
 - Crosstalk analysis
 - Jitter analysis
- Carrier board schematic and layout (possibly)
- Hardware testing



GUI LAYOUT

BER

Channel Select

1 2 3 4 5 6 7 8 9

Frequency

100 MHz

200 MHz

300 MHz

400MHz

Pattern

Fixed Random

JITTER

Periodic

Duty Cycle

Phase

10°

20°

30°

45°

CHIP SELECT

1	2	3
4	5	6
7	8	9

Cross Talk on channel

1 2 3 4 5 6 7 8 9

Cross talk Pattern

Random Worst



DESIGN OF A TEST SET-UP FOR THE CHARACTERIZATION OF HIGH SPEED ITS SERIAL DATA LINKS



Objectives

- Bit error rate evaluation at various data rates
- Cross talk analysis between data links
- Power analysis

Key Tasks

- Specification design of the test plan (can be seen in GUI)
- Schematic design of test board
- Firmware development

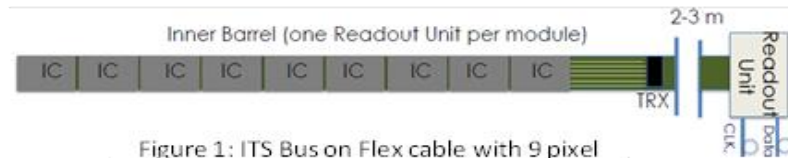
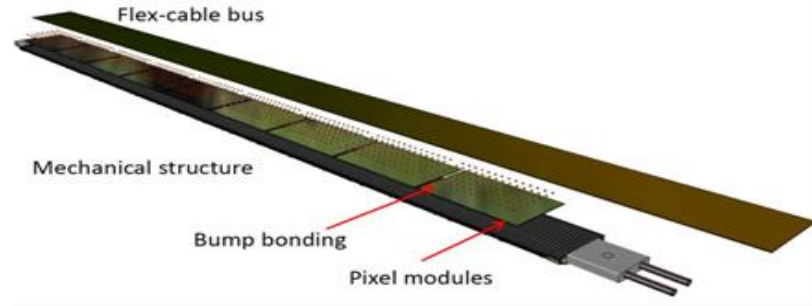
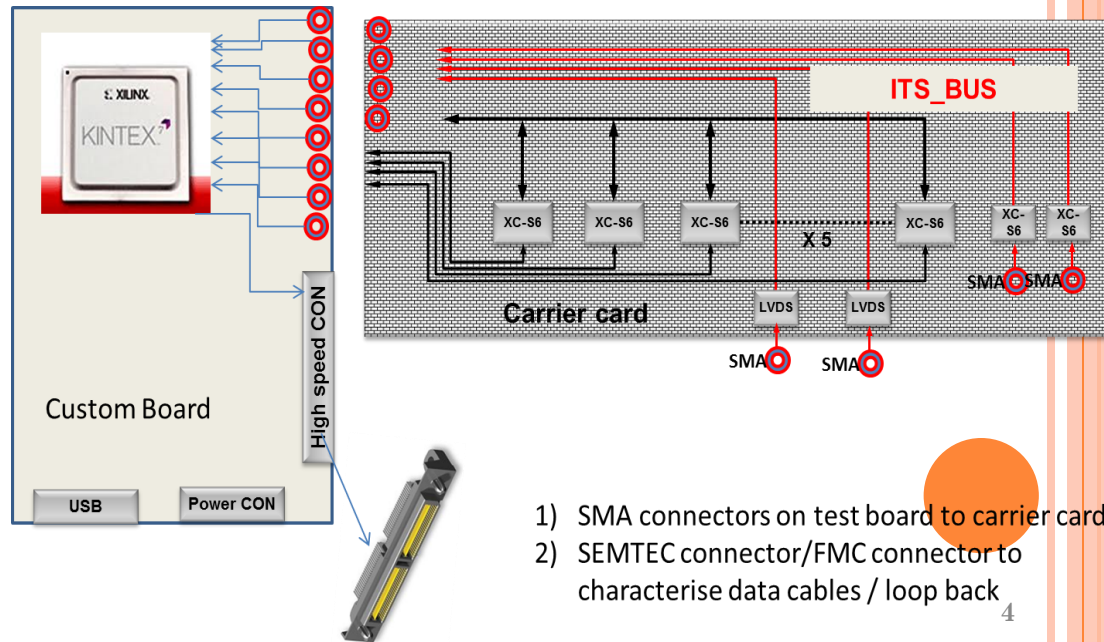
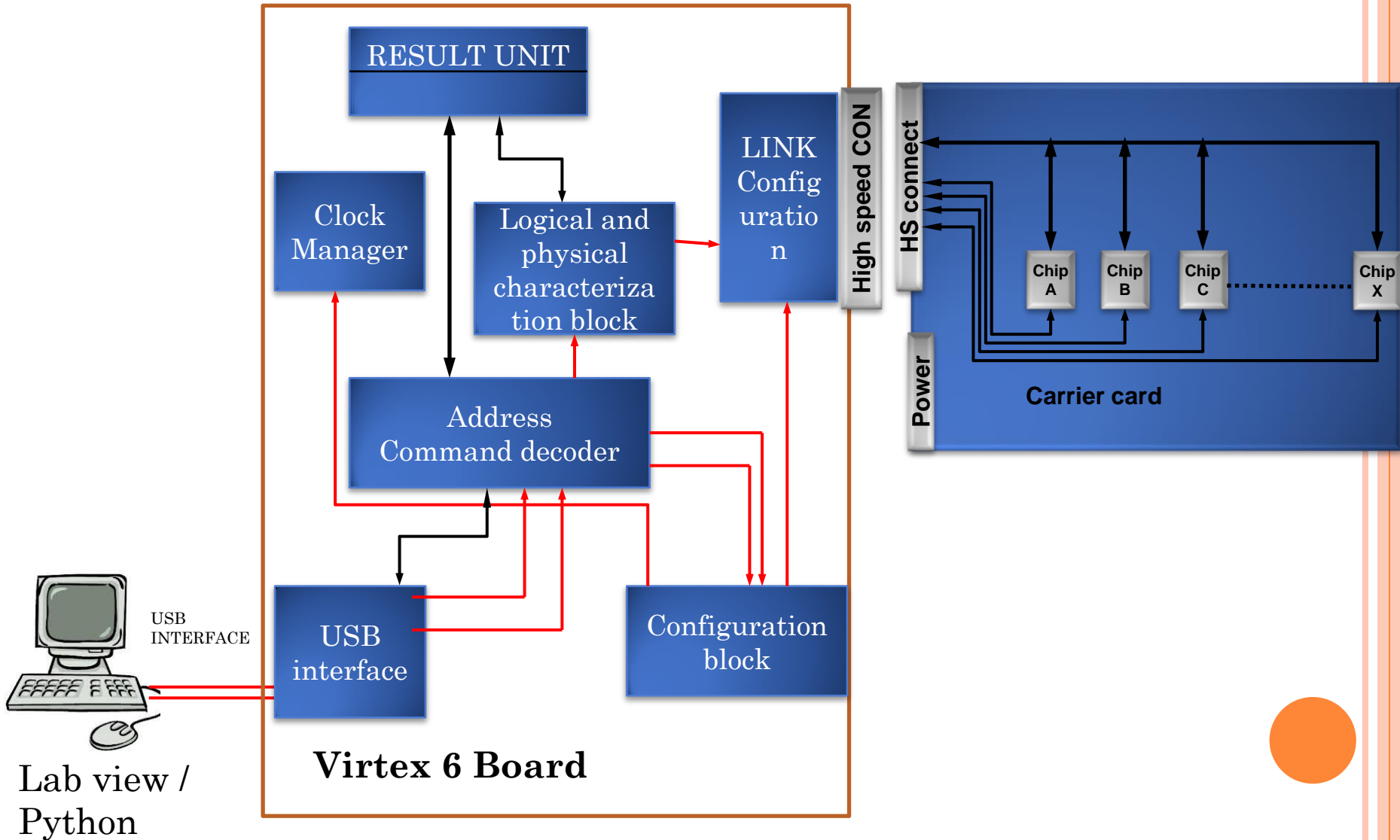


Figure 1: ITS Bus on Flex cable with 9 pixel



- 1) SMA connectors on test board to carrier card
- 2) SEMTEC connector/FMC connector to characterise data cables / loop back

TEST SETUP



BIT ERROR RATE TESTING

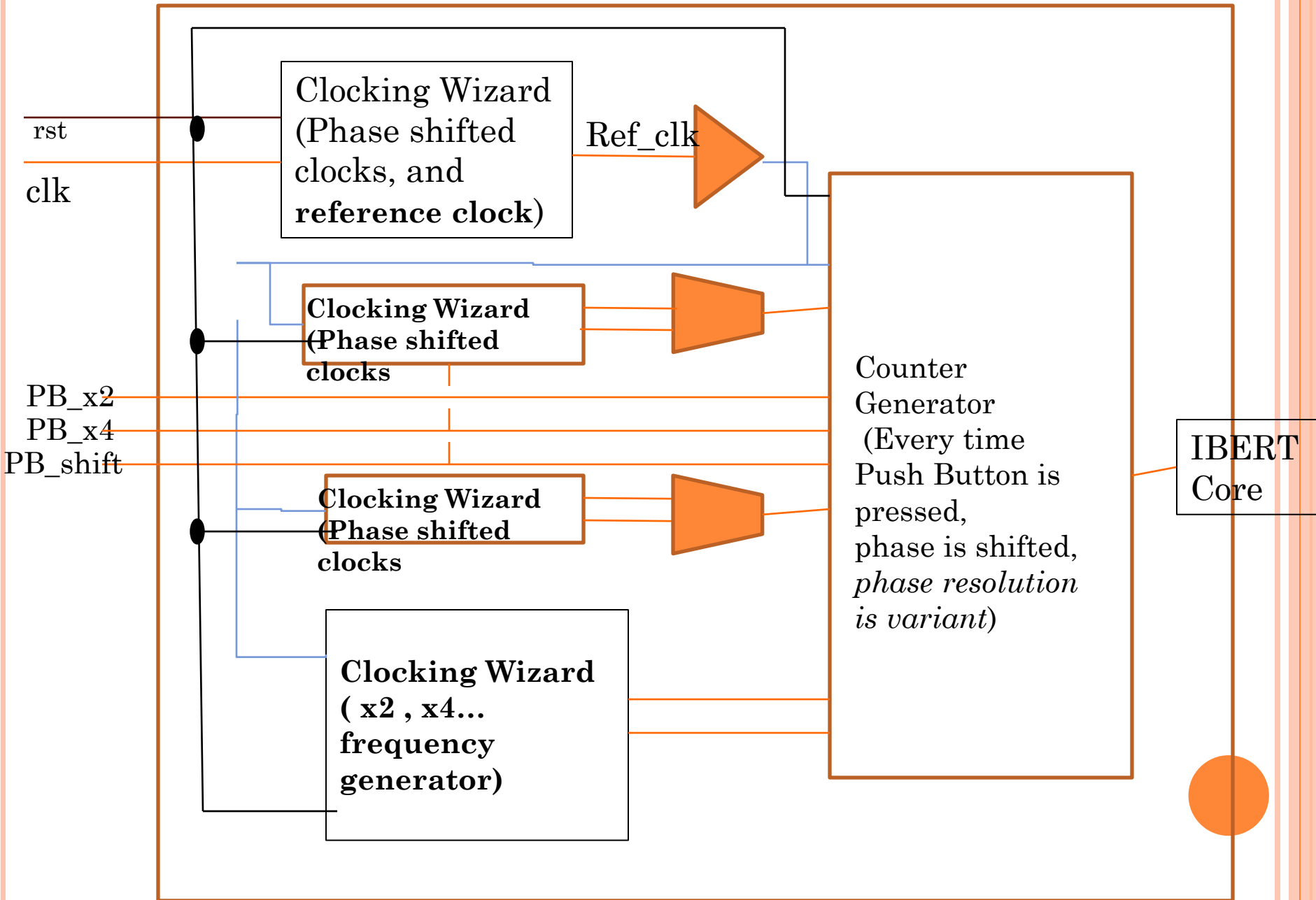
- **Generating clocks with different phases and frequencies to characterize BER.**

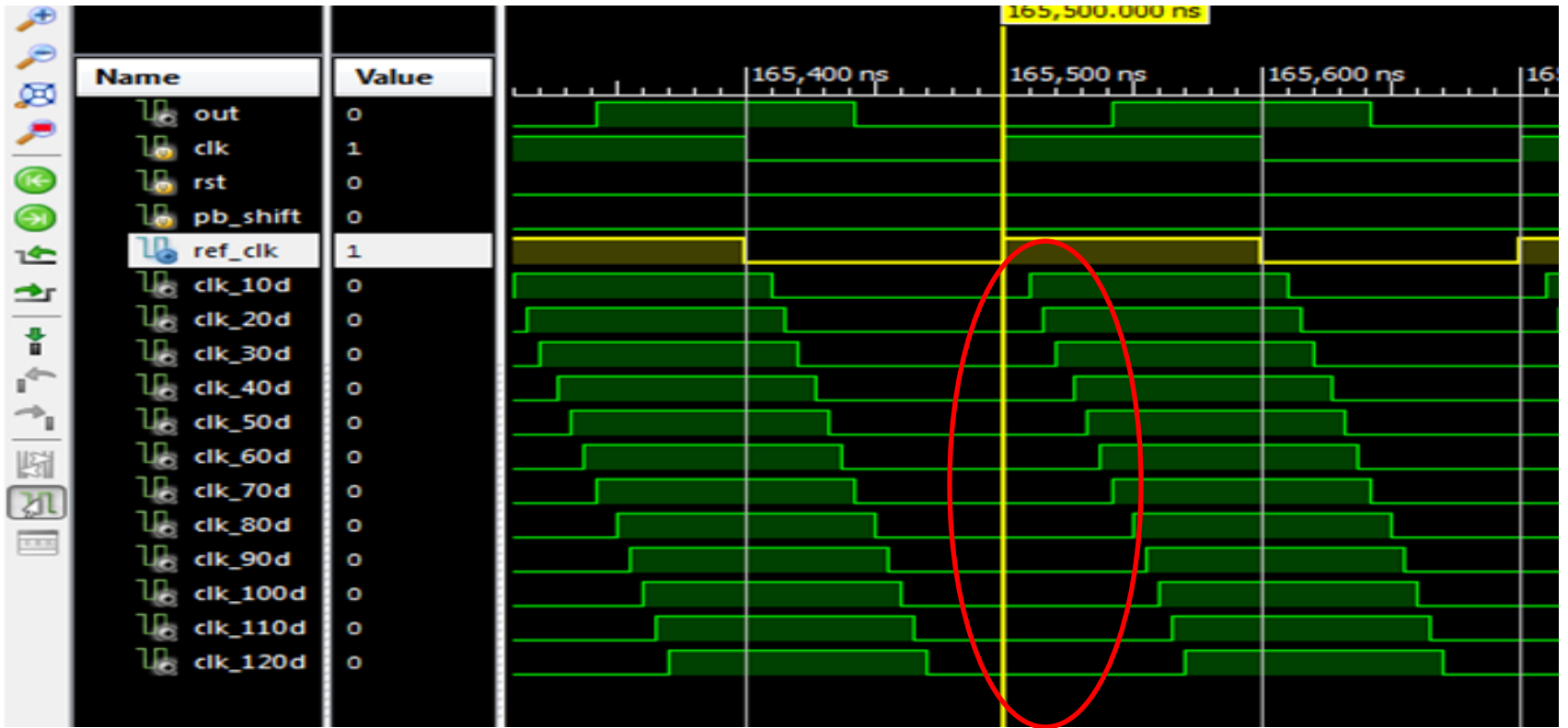
Using system clock as input, generating different shifts with as minimum resolution as possible.

Integrating shifted clocks to check BER



DATA FLOW DIAGRAM of Clock generation





- ref_clk is taken as input clk 50MHz upto 1GHz, rest are shifted clocks with different phase and frequency compared to ref_clk.
- shifted clocks with 50 MHz, have been generated. Each being shifted to 10^0 (simulation, 9^0 to 11^0 actual) as compared to last shift.
- These clocks will now taken as input to check BER, at different phases and frequencies



FUTURE WORK

- Different data patterns are sent at different phases and frequencies.
- Jitter Analysis to be done on different clocks.
- To figure out at what phase and frequency, optimum results are achieved.

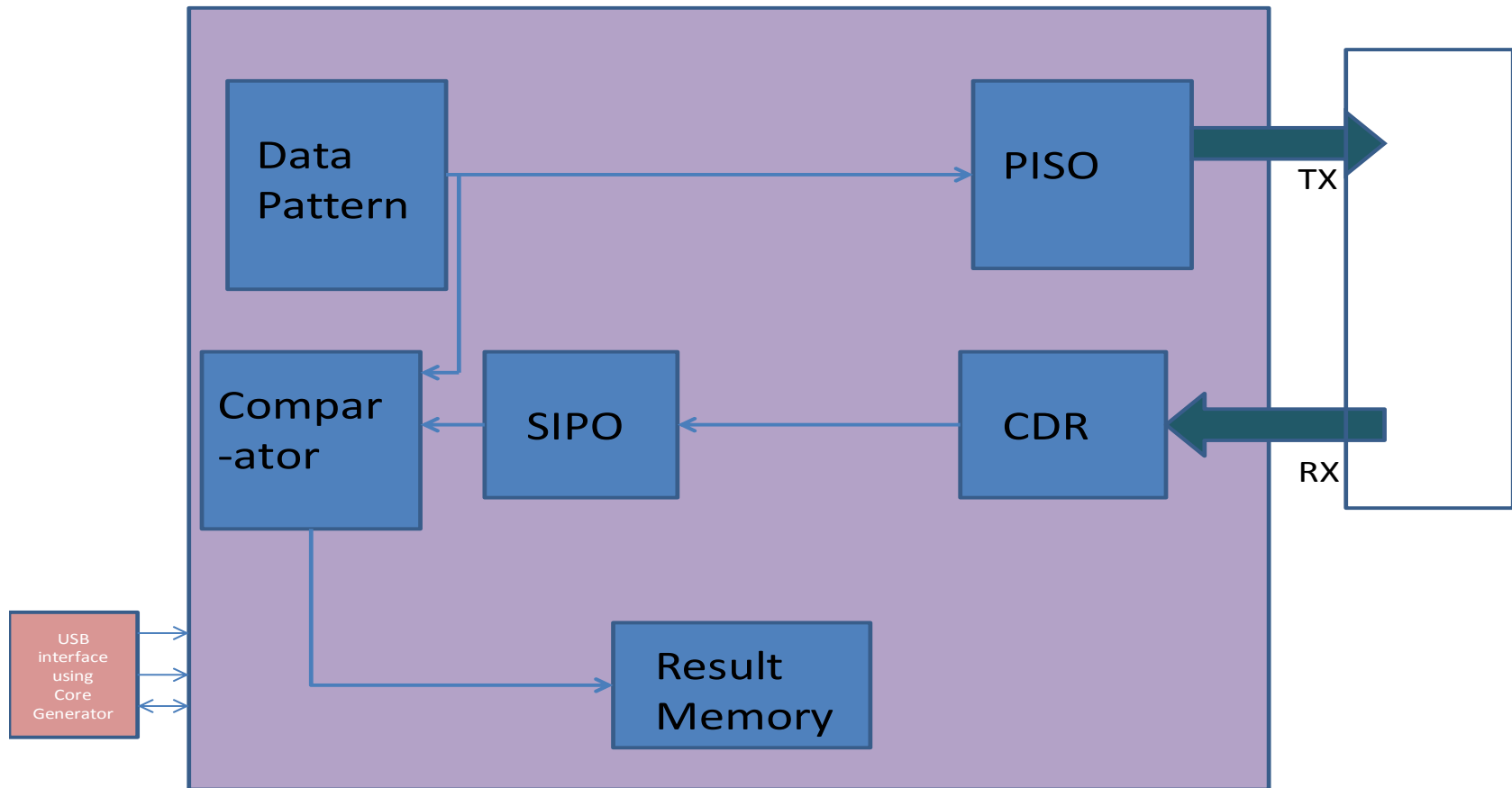


IBERT

- The ChipScope™ Pro Integrated Bit Error Ratio Tester (IBERT) core for Virtex-6 GTX transceivers is a customizable core that can be used to evaluate and monitor the health of Virtex-6 GTX Transceivers.
- The design includes pattern generators and checkers implemented in FPGA logic, as well as access to the ports and dynamic reconfiguration port (DRP) attributes of the GTX transceivers.
- **Software Requirements**
 - Core Generator
 - Chip-scope Pro Analyzer
- **Hardware Requirements**
 - Virtex-6, ML605
 - SMA Cables



DESIGN OF BIT ERROR RATE TESTER



HARDWARE SETUP AND INITIAL SETTINGS & RESULTS



Hardware
setup

IBERT Console - DEV:1 MyDevice1 (XC6VLX240T) UNIT:1_0 MyIBERT V6 GTX1_0 (IBERT V6 GTX)

MGT/IBERT Settings | DRP Settings | Port Settings | Sweep Test Settings

	GTX_X0Y16	GTX_X0Y17	GTX_X0Y18	GTX_X0Y19
MGT Alias	GTX0_116	GTX1_116	GTX2_116	GTX3_116
Tile Location	GTX_X0Y16	GTX_X0Y17	GTX_X0Y18	GTX_X0Y19
MGT Link Status	No Link	No Link	5.004 Gbps	No Link
MGT Edit Line Rate	5.0 Gbps	5.0 Gbps	5.0 Gbps	1.25 Gbps
TX PLL Status	LOCKED	LOCKED	LOCKED	LOCKED
RX PLL Status	LOCKED	LOCKED	LOCKED	LOCKED
Loopback Mode	None	None	None	None
Channel Reset	Reset	Reset	Reset	Reset
TX Polarity Invert	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
TX Error Inject	Inject	Inject	Inject	Inject
TX Diff Output Swing	590 mV (0110)	590 mV (0110)	590 mV (0110)	590 mV (0110)
TX Pre-Emphasis	0.000 dB (0000)	0.000 dB (0000)	0.250 dB (0010)	0.000 dB (0000)
TX Post-Emphasis	0.000 dB (00000)	0.000 dB (00000)	0.000 dB (00000)	0.000 dB (00000)
RX Polarity Invert	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
RX AC Coupling Enable	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
RX Termination Voltage	MGTAVTT *	MGTAVTT *	MGTAVTT *	MGTAVTT *
RX Equalization	0	0	0	0
DFEYEDACMON	19.3 mV	6.4 mV	51.6 mV	58.1 mV
DFETAPOVRD	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>
DFETAP1	0	0	0	0
DFETAP2	0	0	0	0
DFETAP3	0	0	0	0
DFETAP4	0	0	0	0
RX Samolno Point	76 0.598 UI	76 0.598 UI	6 0.039 UI	76 0.598 UI

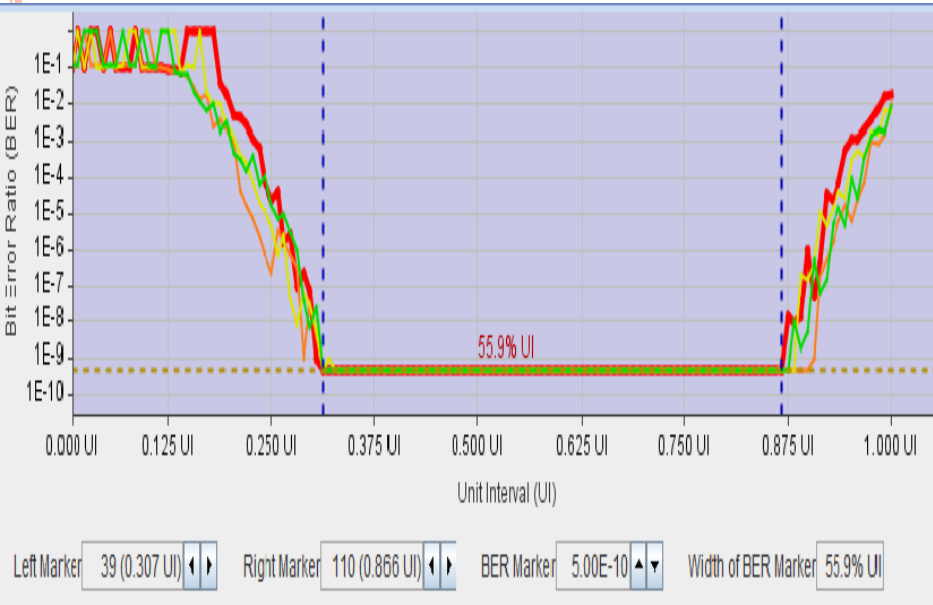
IBERT Initial
Settings



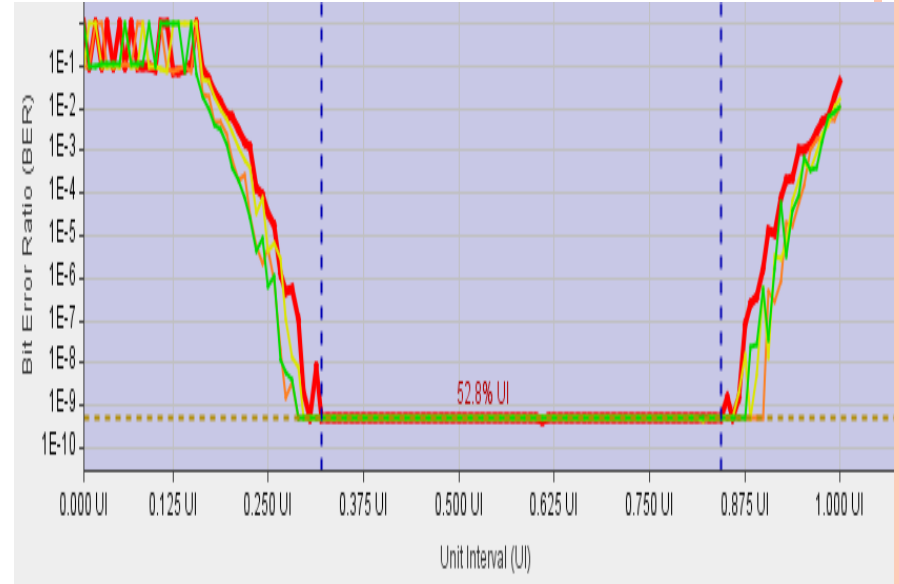
Bathtub Curve to Calculate Bit Error Rate (SMA)

- Line rate: 2.5 Gbps. Frequency 200Mhz

Length 1foot



Length 2feet

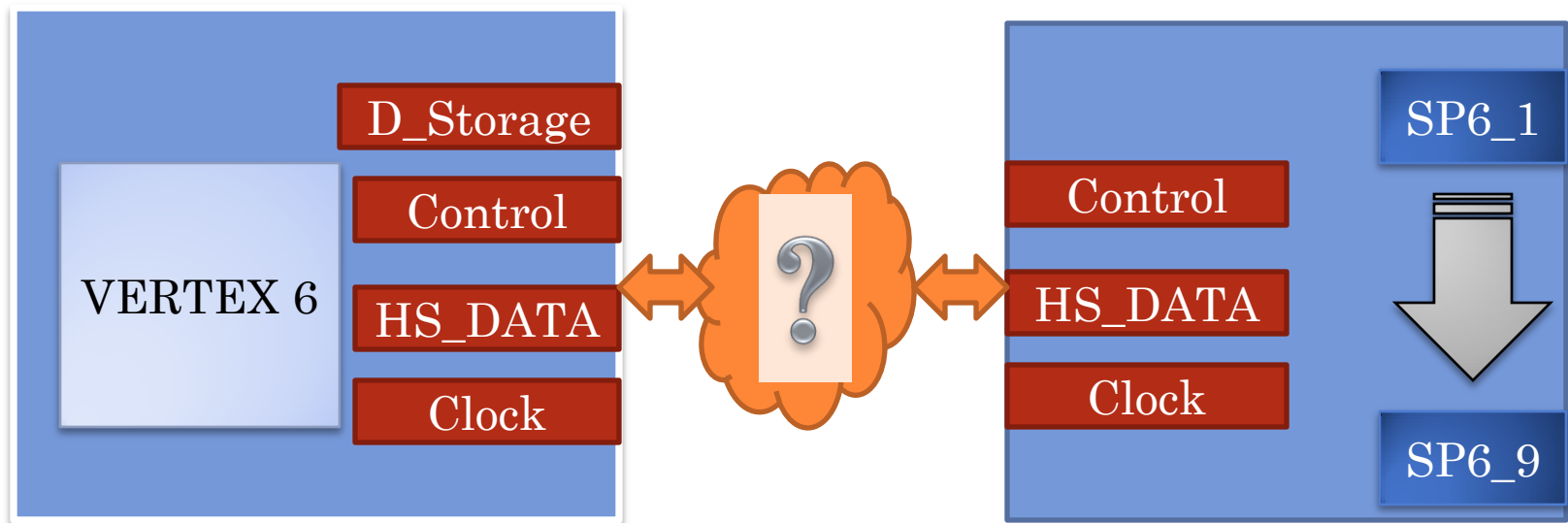


UI OF BATHTUB CURVE @ SYSTEM FREQ 200MHZ

Line rate	1 Foot	2 Feet
2.5 Gbps	55.9%	52.8%
3.125 Gbps	44.5%	38.6%
5 Gbps	36.2.3%	32.3%



BOARD LEVEL COMPATIBILITY BETWEEN MASTER CARD & CARRIER CARD



CARRIER BOARD SCHEMATIC AND LAYOUT

CONTROL

Master Card

- Master Clock 40 MHz
- Chip Select IC
 - Controlling Carrier Card
- JTAG Header
 - External Programming

Carrier Card

- Chip Select IC
 - Enabling Spartan-6 on Carrier Card
- JTAG Header
 - Programming Through Master Card

HIGH SPEED DATA

- Connector Configuration
- Routing Technique
 - Differential Pair
 - Length Tuning
 - Signal Integrity Analysis

- Connector Configuration
- Routing Technique
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 - Length Tuning
 - Signal Integrity Analysis



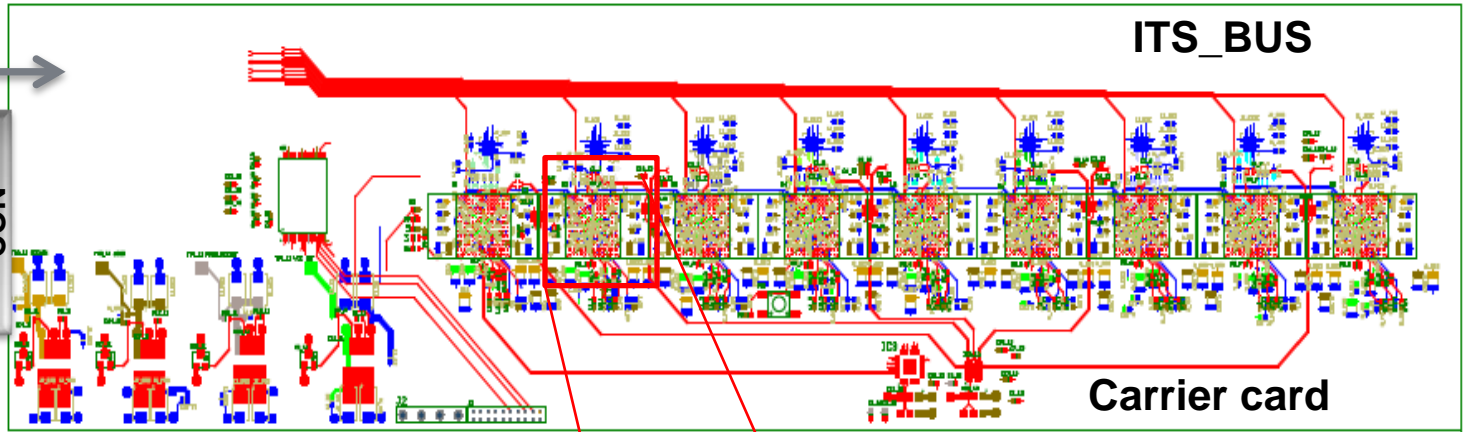
PURPOSED DESIGN TO TEST SERIAL LINK CHARACTERIZATION

Link to be Characterized

FPGA
Xilinx
Board

High speed
CON

High speed
CON



- Master Card Design under Validation.
- Board Design Layout under Process.

Spartan 6
as test chip



HARDWARE SETUP



Agilent Infiniium 9000 Series
Oscilloscopes



Keysight 81150A Pulse Function
Arbitrary Noise Generators
ML605-Vitex 6

